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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	360
Number of Logic Elements/Cells	2880
Total RAM Bits	40960
Number of I/O	102
Number of Gates	199000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1k50tc144-3n

General Description

Altera® ACEX 1K devices provide a die-efficient, low-cost architecture by combining look-up table (LUT) architecture with EABs. LUT-based logic provides optimized performance and efficiency for data-path, register intensive, mathematical, or digital signal processing (DSP) designs, while EABs implement RAM, ROM, dual-port RAM, or first-in first-out (FIFO) functions. These elements make ACEX 1K suitable for complex logic functions and memory functions such as digital signal processing, wide data-path manipulation, data transformation and microcontrollers, as required in high-performance communications applications. Based on reconfigurable CMOS SRAM elements, the ACEX 1K architecture incorporates all features necessary to implement common gate array megafunctions, along with a high pin count to enable an effective interface with system components. The advanced process and the low voltage requirement of the 2.5-V core allow ACEX 1K devices to meet the requirements of low-cost, high-volume applications ranging from DSL modems to low-cost switches.

The ability to reconfigure ACEX 1K devices enables complete testing prior to shipment and allows the designer to focus on simulation and design verification. ACEX 1K device reconfigurability eliminates inventory management for gate array designs and test vector generation for fault coverage.

Table 4 shows ACEX 1K device performance for some common designs. All performance results were obtained with Synopsys DesignWare or LPM functions. Special design techniques are not required to implement the applications; the designer simply infers or instantiates a function in a Verilog HDL, VHDL, Altera Hardware Description Language (AHDL), or schematic design file.

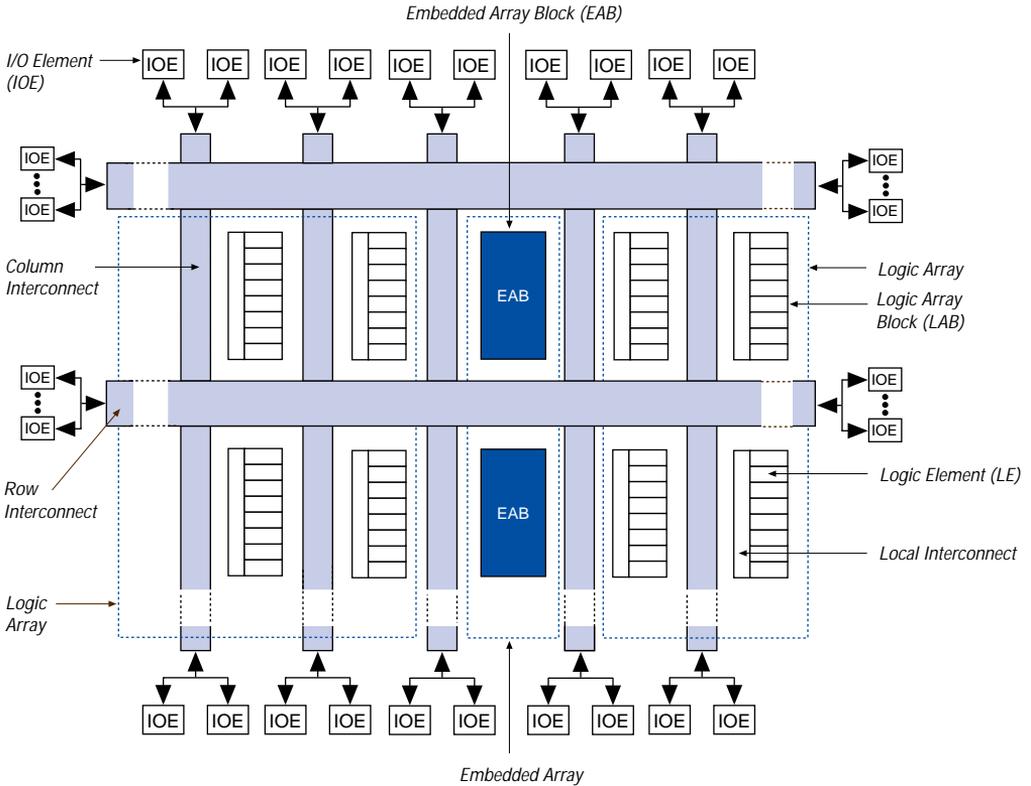
Table 4. ACEX 1K Device Performance

Application	Resources Used		Performance			Units
	LEs	EABs	Speed Grade			
			-1	-2	-3	
16-bit loadable counter	16	0	285	232	185	MHz
16-bit accumulator	16	0	285	232	185	MHz
16-to-1 multiplexer (1)	10	0	3.5	4.5	6.6	ns
16-bit multiplier with 3-stage pipeline(2)	592	0	156	131	93	MHz
256 × 16 RAM read cycle speed (2)	0	1	278	196	143	MHz
256 × 16 RAM write cycle speed (2)	0	1	185	143	111	MHz

Notes:

- (1) This application uses combinatorial inputs and outputs.
- (2) This application uses registered inputs and outputs.

Figure 1. ACEX 1K Device Block Diagram



ACEX 1K devices provide six dedicated inputs that drive the flipflops' control inputs and ensure the efficient distribution of high-speed, low-skew (less than 1.0 ns) control signals. These signals use dedicated routing channels that provide shorter delays and lower skews than the FastTrack Interconnect routing structure. Four of the dedicated inputs drive four global signals. These four global signals can also be driven by internal logic, providing an ideal solution for a clock divider or an internally generated asynchronous clear signal that clears many registers in the device.

Each LAB provides four control signals with programmable inversion that can be used in all eight LEs. Two of these signals can be used as clocks, the other two can be used for clear/preset control. The LAB clocks can be driven by the dedicated clock input pins, global signals, I/O signals, or internal signals via the LAB local interconnect. The LAB preset and clear control signals can be driven by the global signals, I/O signals, or internal signals via the LAB local interconnect. The global control signals are typically used for global clock, clear, or preset signals because they provide asynchronous control with very low skew across the device. If logic is required on a control signal, it can be generated in one or more LEs in any LAB and driven into the local interconnect of the target LAB. In addition, the global control signals can be generated from LE outputs.

Logic Element

The LE, the smallest unit of logic in the ACEX 1K architecture, has a compact size that provides efficient logic utilization. Each LE contains a 4-input LUT, which is a function generator that can quickly compute any function of four variables. In addition, each LE contains a programmable flipflop with a synchronous clock enable, a carry chain, and a cascade chain. Each LE drives both the local and the FastTrack Interconnect routing structure. [Figure 8](#) shows the ACEX 1K LE.

LE Operating Modes

The ACEX 1K LE can operate in the following four modes:

- Normal mode
- Arithmetic mode
- Up/down counter mode
- Clearable counter mode

Each of these modes uses LE resources differently. In each mode, seven available inputs to the LE—the four data inputs from the LAB local interconnect, the feedback from the programmable register, and the carry-in and cascade-in from the previous LE—are directed to different destinations to implement the desired logic function. Three inputs to the LE provide clock, clear, and preset control for the register. The Altera software, in conjunction with parameterized functions such as LPM and DesignWare functions, automatically chooses the appropriate mode for common functions such as counters, adders, and multipliers. If required, the designer can also create special-purpose functions that use a specific LE operating mode for optimal performance.

The architecture provides a synchronous clock enable to the register in all four modes. The Altera software can set `DATA1` to enable the register synchronously, providing easy implementation of fully synchronous designs.

Figure 11 shows the ACEX 1K LE operating modes.

Normal Mode

The normal mode is suitable for general logic applications and wide decoding functions that can take advantage of a cascade chain. In normal mode, four data inputs from the LAB local interconnect and the carry-in are inputs to a 4-input LUT. The compiler automatically selects the carry-in or the `DATA3` signal as one of the inputs to the LUT. The LUT output can be combined with the cascade-in signal to form a cascade chain through the cascade-out signal. Either the register or the LUT can be used to drive both the local interconnect and the FastTrack Interconnect routing structure at the same time.

The LUT and the register in the LE can be used independently (register packing). To support register packing, the LE has two outputs; one drives the local interconnect, and the other drives the FastTrack Interconnect routing structure. The `DATA4` signal can drive the register directly, allowing the LUT to compute a function that is independent of the registered signal; a 3-input function can be computed in the LUT, and a fourth independent signal can be registered. Alternatively, a 4-input function can be generated, and one of the inputs to this function can be used to drive the register. The register in a packed LE can still use the clock enable, clear, and preset signals in the LE. In a packed LE, the register can drive the FastTrack Interconnect routing structure while the LUT drives the local interconnect, or vice versa.

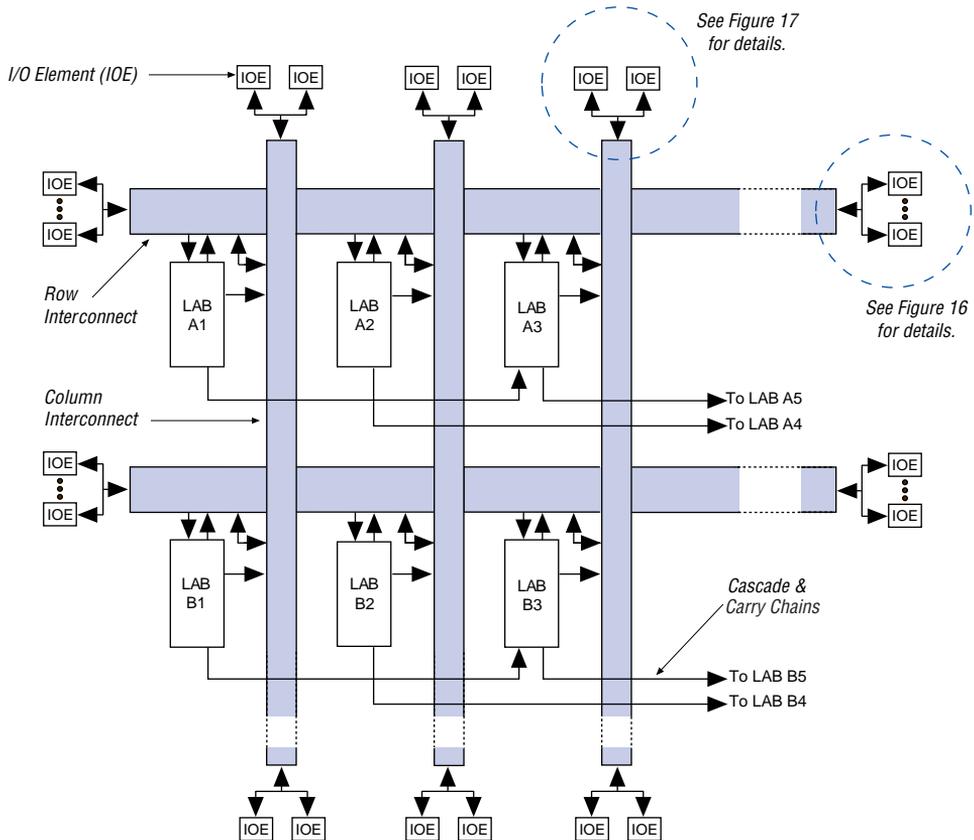
Arithmetic Mode

The arithmetic mode offers two 3-input LUTs that are ideal for implementing adders, accumulators, and comparators. One LUT computes a 3-input function; the other generates a carry output. As shown in [Figure 11](#), the first LUT uses the carry-in signal and two data inputs from the LAB local interconnect to generate a combinatorial or registered output. For example, in an adder, this output is the sum of three signals: `a`, `b`, and carry-in. The second LUT uses the same three signals to generate a carry-out signal, thereby creating a carry chain. The arithmetic mode also supports simultaneous use of the cascade chain.

Up/Down Counter Mode

The up/down counter mode offers counter enable, clock enable, synchronous up/down control, and data loading options. These control signals are generated by the data inputs from the LAB local interconnect, the carry-in signal, and output feedback from the programmable register. Two 3-input LUTs are used; one generates the counter data, and the other generates the fast carry bit. A 2-to-1 multiplexer provides synchronous loading. Data can also be loaded asynchronously with the clear and preset register control signals without using the LUT resources.

Figure 14. ACEX 1K Interconnect Resources



I/O Element

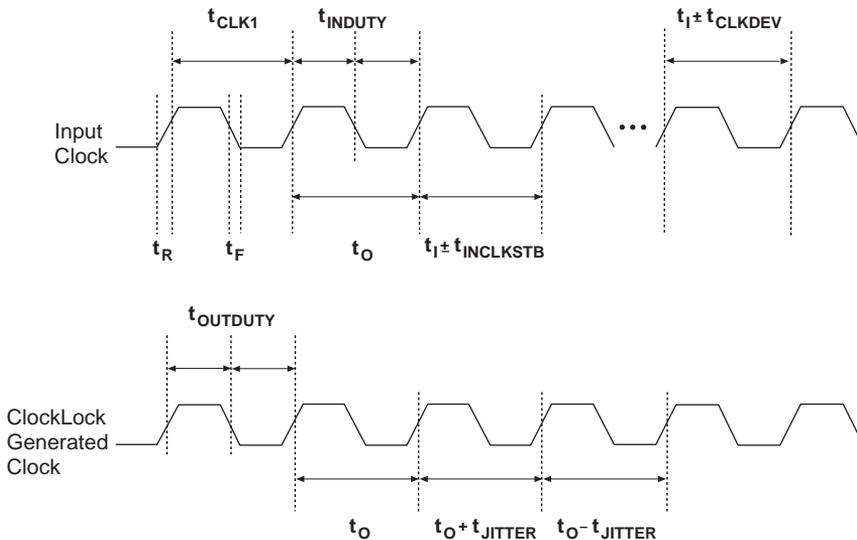
An IOE contains a bidirectional I/O buffer and a register that can be used either as an input register for external data that requires a fast setup time or as an output register for data that requires fast clock-to-output performance. In some cases, using an LE register for an input register will result in a faster setup time than using an IOE register. IOEs can be used as input, output, or bidirectional pins. The compiler uses the programmable inversion option to invert signals from the row and column interconnect automatically where appropriate. For bidirectional registered I/O implementation, the output register should be in the IOE and the data input and output enable registers should be LE registers placed adjacent to the bidirectional pin. Figure 15 shows the bidirectional I/O registers.

For designs that require both a multiplied and non-multiplied clock, the clock trace on the board can be connected to the GCLK1 pin. In the Altera software, the GCLK1 pin can feed both the ClockLock and ClockBoost circuitry in the ACEX 1K device. However, when both circuits are used, the other clock pin cannot be used.

ClockLock & ClockBoost Timing Parameters

For the ClockLock and ClockBoost circuitry to function properly, the incoming clock must meet certain requirements. If these specifications are not met, the circuitry may not lock onto the incoming clock, which generates an erroneous clock within the device. The clock generated by the ClockLock and ClockBoost circuitry must also meet certain specifications. If the incoming clock meets these requirements during configuration, the ClockLock and ClockBoost circuitry will lock onto the clock during configuration. The circuit will be ready for use immediately after configuration. Figure 19 shows the incoming and generated clock specifications.

Figure 19. Specifications for the Incoming & Generated Clocks *Note (1)*



Note:

- (1) The t_I parameter refers to the nominal input clock period; the t_O parameter refers to the nominal output clock period.

PCI Pull-Up Clamping Diode Option

ACEX 1K devices have a pull-up clamping diode on every I/O, dedicated input, and dedicated clock pin. PCI clamping diodes clamp the signal to the V_{CCIO} value and are required for 3.3-V PCI compliance. Clamping diodes can also be used to limit overshoot in other systems.

Clamping diodes are controlled on a pin-by-pin basis. When V_{CCIO} is 3.3 V, a pin that has the clamping diode option turned on can be driven by a 2.5-V or 3.3-V signal, but not a 5.0-V signal. When V_{CCIO} is 2.5 V, a pin that has the clamping diode option turned on can be driven by a 2.5-V signal, but not a 3.3-V or 5.0-V signal. Additionally, a clamping diode can be activated for a subset of pins, which allows a device to bridge between a 3.3-V PCI bus and a 5.0-V device.

Slew-Rate Control

The output buffer in each IOE has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A slower slew rate reduces system noise and adds a maximum delay of 4.3 ns. The fast slew rate should be used for speed-critical outputs in systems that are adequately protected against noise. Designers can specify the slew rate pin-by-pin or assign a default slew rate to all pins on a device-wide basis. The slow slew rate setting affects only the falling edge of the output.

Open-Drain Output Option

ACEX 1K devices provide an optional open-drain output (electrically equivalent to open-collector output) for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-OR plane.

MultiVolt I/O Interface

The ACEX 1K device architecture supports the MultiVolt I/O interface feature, which allows ACEX 1K devices in all packages to interface with systems of differing supply voltages. These devices have one set of V_{CC} pins for internal operation and input buffers (V_{CCINT}), and another set for I/O output drivers (V_{CCIO}).

The V_{CCINT} pins must always be connected to a 2.5-V power supply. With a 2.5-V V_{CCINT} level, input voltages are compatible with 2.5-V, 3.3-V, and 5.0-V inputs. The V_{CCIO} pins can be connected to either a 2.5-V or 3.3-V power supply, depending on the output requirements. When the V_{CCIO} pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When the V_{CCIO} pins are connected to a 3.3-V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with V_{CCIO} levels higher than 3.0 V achieve a faster timing delay of t_{OD2} instead of t_{OD1} .

Table 13 summarizes ACEX 1K MultiVolt I/O support.

V_{CCIO} (V)	Input Signal (V)			Output Signal (V)		
	2.5	3.3	5.0	2.5	3.3	5.0
2.5	✓	✓ (1)	✓ (1)	✓		
3.3	✓	✓	✓ (1)	✓ (2)	✓	✓

Notes:

- (1) The PCI clamping diode must be disabled on an input which is driven with a voltage higher than V_{CCIO} .
- (2) When $V_{CCIO} = 3.3$ V, an ACEX 1K device can drive a 2.5-V device that has 3.3-V tolerant inputs.

Open-drain output pins on ACEX 1K devices (with a pull-up resistor to the 5.0-V supply) can drive 5.0-V CMOS input pins that require a higher V_{IH} than LVTTL. When the open-drain pin is active, it will drive low. When the pin is inactive, the resistor will pull up the trace to 5.0 V, thereby meeting the CMOS V_{OH} requirement. The open-drain pin will only drive low or tri-state; it will never drive high. The rise time is dependent on the value of the pull-up resistor and load impedance. The I_{OL} current specification should be considered when selecting a pull-up resistor.

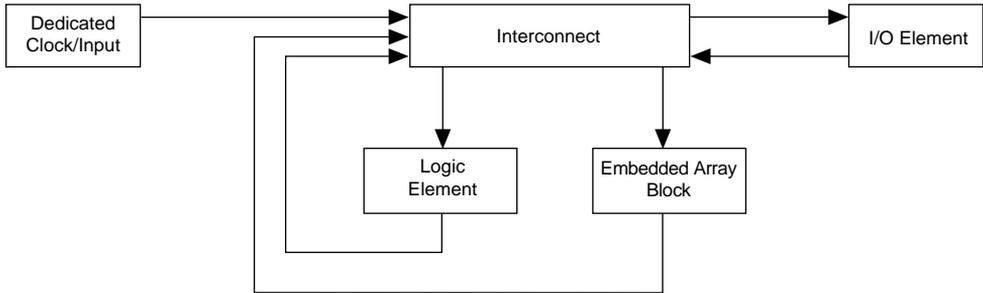
Because ACEX 1K devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. The V_{CCIO} and V_{CCINT} power planes can be powered in any order.

Signals can be driven into ACEX 1K devices before and during power up without damaging the device. Additionally, ACEX 1K devices do not drive out during power up. Once operating conditions are reached, ACEX 1K devices operate as specified by the user.

Power Sequencing & Hot-Socketing

Figure 24 shows the overall timing model, which maps the possible paths to and from the various elements of the ACEX 1K device.

Figure 24. ACEX 1K Device Timing Model



Figures 25 through 28 show the delays that correspond to various paths and functions within the LE, IOE, EAB, and bidirectional timing models.

Figure 25. ACEX 1K Device LE Timing Model

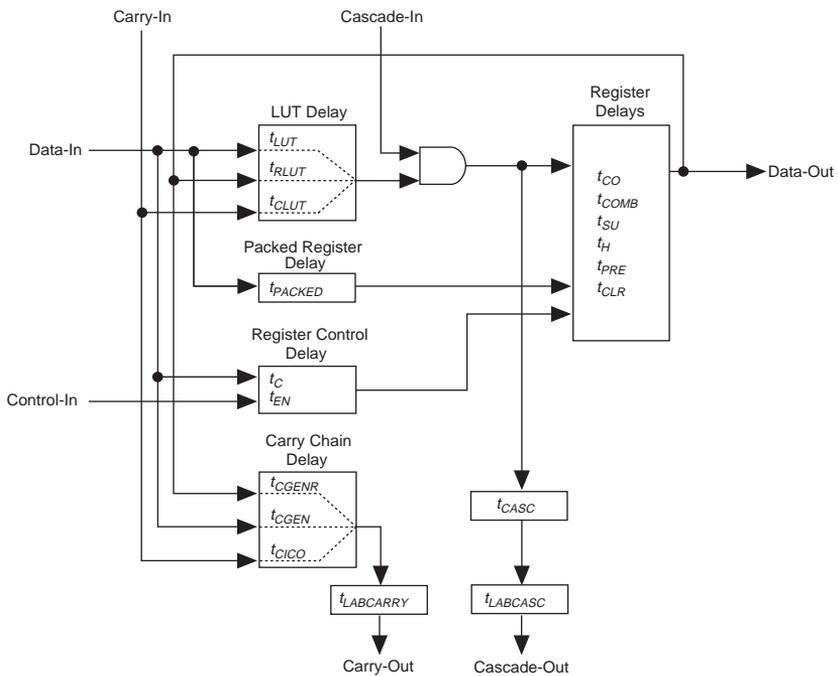
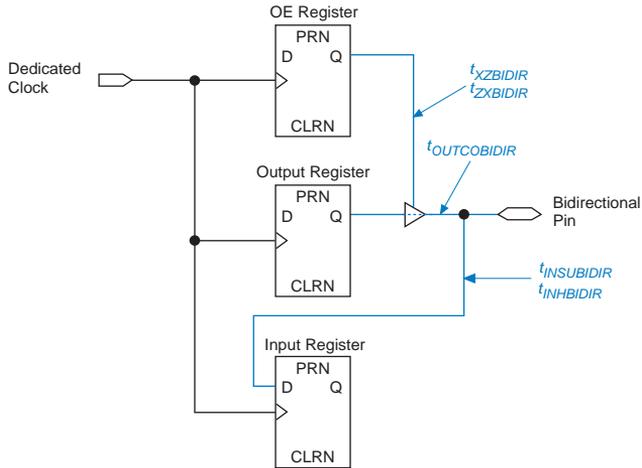


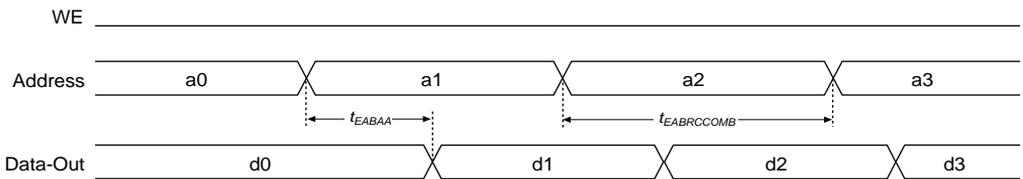
Figure 28. Synchronous Bidirectional Pin External Timing Model



Tables 29 and 30 show the asynchronous and synchronous timing waveforms, respectively, for the EAB macroparameters in Table 24.

Figure 29. EAB Asynchronous Timing Waveforms

EAB Asynchronous Read



EAB Asynchronous Write

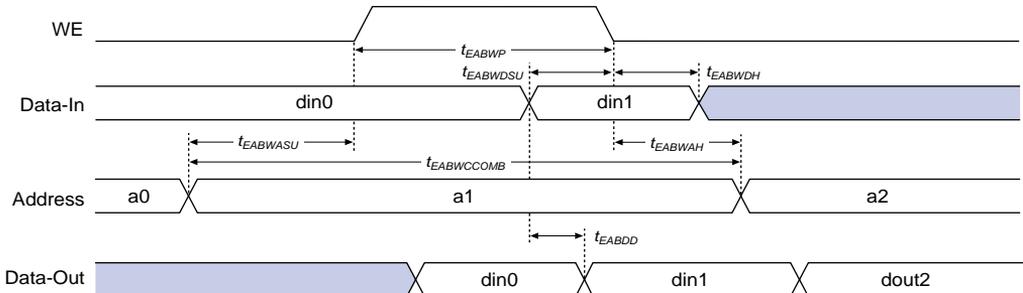
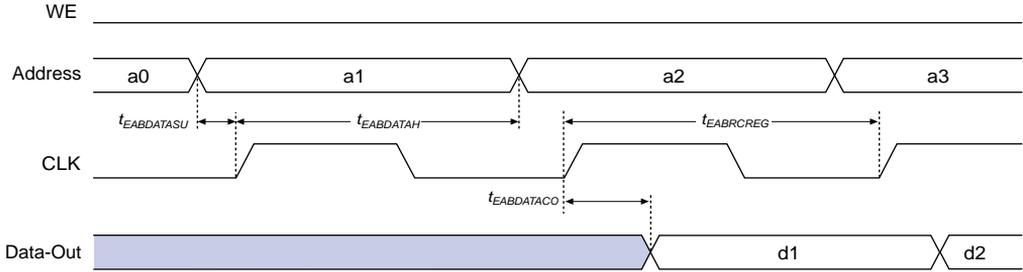
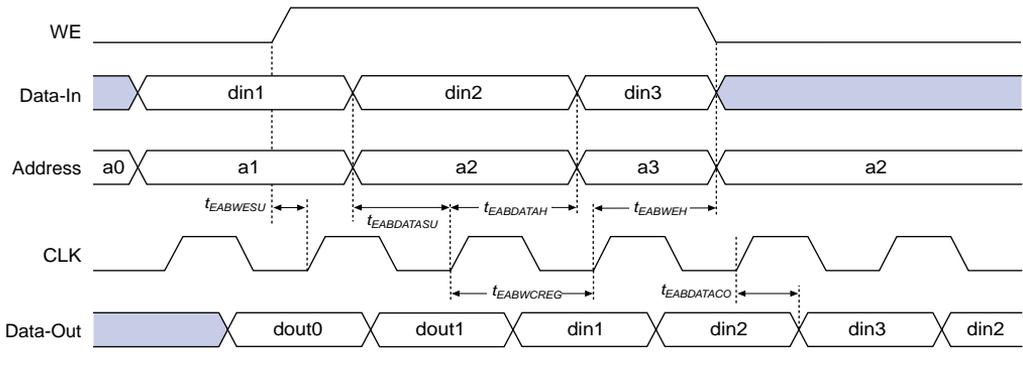


Figure 30. EAB Synchronous Timing Waveforms

EAB Synchronous Read



EAB Synchronous Write (EAB Output Registers Used)



Tables 22 through 26 describe the ACEX 1K device internal timing parameters.

Symbol	Parameter	Conditions
t_{LUT}	LUT delay for data-in	
t_{CLUT}	LUT delay for carry-in	
t_{RLUT}	LUT delay for LE register feedback	
t_{PACKED}	Data-in to packed register delay	
t_{EN}	LE register enable delay	
t_{CICO}	Carry-in to carry-out delay	
t_{CGEN}	Data-in to carry-out delay	
t_{CGENR}	LE register feedback to carry-out delay	

Table 26. Interconnect Timing Microparameters *Note (1)*

Symbol	Parameter	Conditions
$t_{DIN2IOE}$	Delay from dedicated input pin to IOE control input	(7)
t_{DIN2LE}	Delay from dedicated input pin to LE or EAB control input	(7)
$t_{DIN2DATA}$	Delay from dedicated input or clock to LE or EAB data	(7)
$t_{DCLK2IOE}$	Delay from dedicated clock pin to IOE clock	(7)
$t_{DCLK2LE}$	Delay from dedicated clock pin to LE or EAB clock	(7)
$t_{SAMELAB}$	Routing delay for an LE driving another LE in the same LAB	(7)
$t_{SAMEROW}$	Routing delay for a row IOE, LE, or EAB driving a row IOE, LE, or EAB in the same row	(7)
$t_{SAMECOLUMN}$	Routing delay for an LE driving an IOE in the same column	(7)
$t_{DIFFROW}$	Routing delay for a column IOE, LE, or EAB driving an LE or EAB in a different row	(7)
$t_{TWOROWS}$	Routing delay for a row IOE or EAB driving an LE or EAB in a different row	(7)
$t_{LEPERIPH}$	Routing delay for an LE driving a control signal of an IOE via the peripheral control bus	(7)
$t_{LABCARRY}$	Routing delay for the carry-out signal of an LE driving the carry-in signal of a different LE in a different LAB	
$t_{LABCASC}$	Routing delay for the cascade-out signal of an LE driving the cascade-in signal of a different LE in a different LAB	

Notes to tables:

- (1) Microparameters are timing delays contributed by individual architectural elements. These parameters cannot be measured explicitly.
- (2) Operating conditions: $V_{CCIO} = 3.3\text{ V} \pm 10\%$ for commercial or industrial and extended use in ACEX 1K devices
- (3) Operating conditions: $V_{CCIO} = 2.5\text{ V} \pm 5\%$ for commercial or industrial and extended use in ACEX 1K devices.
- (4) Operating conditions: $V_{CCIO} = 2.5\text{ V}$ or 3.3 V .
- (5) Because the RAM in the EAB is self-timed, this parameter can be ignored when the WE signal is registered.
- (6) EAB macroparameters are internal parameters that can simplify predicting the behavior of an EAB at its boundary; these parameters are calculated by summing selected microparameters.
- (7) These parameters are worst-case values for typical applications. Post-compilation timing simulation and timing analysis are required to determine actual worst-case performance.

Tables 27 through 29 describe the ACEX 1K external timing parameters and their symbols.

<i>Table 27. External Reference Timing Parameters</i> <i>Note (1)</i>		
Symbol	Parameter	Conditions
t_{DRR}	Register-to-register delay via four LEs, three row interconnects, and four local interconnects	(2)

<i>Table 28. External Timing Parameters</i>		
Symbol	Parameter	Conditions
t_{INSU}	Setup time with global clock at IOE register	(3)
t_{INH}	Hold time with global clock at IOE register	(3)
t_{OUTCO}	Clock-to-output delay with global clock at IOE register	(3)
t_{PCISU}	Setup time with global clock for registers used in PCI designs	(3), (4)
t_{PCIH}	Hold time with global clock for registers used in PCI designs	(3), (4)
t_{PCICO}	Clock-to-output delay with global clock for registers used in PCI designs	(3), (4)

<i>Table 29. External Bidirectional Timing Parameters</i> <i>Note (3)</i>		
Symbol	Parameter	Conditions
$t_{\text{INSUBIDIR}}$	Setup time for bidirectional pins with global clock at same-row or same-column LE register	
t_{INHBIDIR}	Hold time for bidirectional pins with global clock at same-row or same-column LE register	
$t_{\text{OUTCOBIDIR}}$	Clock-to-output delay for bidirectional pins with global clock at IOE register	Cl = 35 pF
t_{XZBIDIR}	Synchronous IOE output buffer disable delay	Cl = 35 pF
t_{ZXBIDIR}	Synchronous IOE output buffer enable delay, slow slew rate = off	Cl = 35 pF

Notes to tables:

- (1) External reference timing parameters are factory-tested, worst-case values specified by Altera. A representative subset of signal paths is tested to approximate typical device applications.
- (2) Contact Altera Applications for test circuit specifications and test conditions.
- (3) These timing parameters are sample-tested only.
- (4) This parameter is measured with the measurement and test conditions, including load, specified in the *PCI Local Bus Specification, Revision 2.2*.

Table 31. EP1K10 Device IOE Timing Microparameters *Note (1)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		2.6		3.1		4.0	ns
t_{IOC}		0.3		0.4		0.5	ns
t_{IOCO}		0.9		1.0		1.4	ns
t_{IOCOMB}		0.0		0.0		0.0	ns
t_{IOSU}	1.3		1.5		2.0		ns
t_{IOH}	0.9		1.0		1.4		ns
t_{IOCLR}		1.1		1.3		1.7	ns
t_{OD1}		3.1		3.7		4.1	ns
t_{OD2}		2.6		3.3		3.9	ns
t_{OD3}		5.8		6.9		8.3	ns
t_{XZ}		3.8		4.5		5.9	ns
t_{ZX1}		3.8		4.5		5.9	ns
t_{ZX2}		3.3		4.1		5.7	ns
t_{ZX3}		6.5		7.7		10.1	ns
t_{INREG}		3.7		4.3		5.7	ns
t_{IOFD}		0.9		1.0		1.4	ns
t_{INCOMB}		1.9		2.3		3.0	ns

Table 33. EP1K10 Device EAB Internal Timing Macroparameters *Note (1)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
t_{EABAA}		6.7		7.3		7.3	ns
$t_{EABRCCOMB}$	6.7		7.3		7.3		ns
$t_{EABRCREG}$	4.7		4.9		4.9		ns
t_{EABWP}	2.7		2.8		2.8		ns
$t_{EABWCCOMB}$	6.4		6.7		6.7		ns
$t_{EABWCREG}$	7.4		7.6		7.6		ns
t_{EABDD}		6.0		6.5		6.5	ns
$t_{EABDATA CO}$		0.8		0.9		0.9	ns
$t_{EABDATASU}$	1.6		1.7		1.7		ns
$t_{EABDATAH}$	0.0		0.0		0.0		ns
$t_{EABWESU}$	1.4		1.4		1.4		ns
t_{EABWEH}	0.1		0.0		0.0		ns
$t_{EABWDSU}$	1.6		1.7		1.7		ns
t_{EABWDH}	0.0		0.0		0.0		ns
$t_{EABWASU}$	3.1		3.4		3.4		ns
t_{EABWAH}	0.6		0.5		0.5		ns
t_{EABWO}		5.4		5.8		5.8	ns

Table 36. EP1K10 External Bidirectional Timing Parameters *Notes (1), (3)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}}^{(2)}$	2.2		2.3		3.2		ns
$t_{\text{INHBDIR}}^{(2)}$	0.0		0.0		0.0		ns
$t_{\text{OUTCOBDIR}}^{(2)}$	2.0	6.6	2.0	7.8	2.0	9.6	ns
$t_{\text{XZBDIR}}^{(2)}$		8.8		11.2		14.0	ns
$t_{\text{ZXBIDIR}}^{(2)}$		8.8		11.2		14.0	ns
$t_{\text{INSUBIDIR}}^{(4)}$	3.1		3.3		–	–	
$t_{\text{INHBDIR}}^{(4)}$	0.0		0.0		–	–	
$t_{\text{OUTCOBDIR}}^{(4)}$	0.5	5.1	0.5	6.4	–	–	ns
$t_{\text{XZBDIR}}^{(4)}$		7.3		9.2		–	ns
$t_{\text{ZXBIDIR}}^{(4)}$		7.3		9.2		–	ns

Notes to tables:

- (1) All timing parameters are described in Tables 22 through 29 in this data sheet.
- (2) This parameter is measured without the use of the ClockLock or ClockBoost circuits.
- (3) These parameters are specified by characterization.
- (4) This parameter is measured with the use of the ClockLock or ClockBoost circuits.

Tables 37 through 43 show EP1K30 device internal and external timing parameters.

Table 37. EP1K30 Device LE Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		0.7		0.8		1.1	ns
t_{CLUT}		0.5		0.6		0.8	ns
t_{RLUT}		0.6		0.7		1.0	ns
t_{PACKED}		0.3		0.4		0.5	ns
t_{EN}		0.6		0.8		1.0	ns
t_{CICO}		0.1		0.1		0.2	ns
t_{CGEN}		0.4		0.5		0.7	ns
t_{CGENR}		0.1		0.1		0.2	ns
t_{CASC}		0.6		0.8		1.0	ns
t_{C}		0.0		0.0		0.0	ns
t_{CO}		0.3		0.4		0.5	ns

Table 41. EP1K30 Device Interconnect Timing Microparameters *Note (1)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
$t_{DIN2IOE}$		1.8		2.4		2.9	ns
t_{DIN2LE}		1.5		1.8		2.4	ns
$t_{DIN2DATA}$		1.5		1.8		2.2	ns
$t_{DCLK2IOE}$		2.2		2.6		3.0	ns
$t_{DCLK2LE}$		1.5		1.8		2.4	ns
$t_{SAMELAB}$		0.1		0.2		0.3	ns
$t_{SAMEROW}$		2.0		2.4		2.7	ns
$t_{SAMECOLUMN}$		0.7		1.0		0.8	ns
$t_{DIFFROW}$		2.7		3.4		3.5	ns
$t_{TWOROWS}$		4.7		5.8		6.2	ns
$t_{LEPERIPH}$		2.7		3.4		3.8	ns
$t_{LABCARRY}$		0.3		0.4		0.5	ns
$t_{LABCASC}$		0.8		0.8		1.1	ns

Table 42. EP1K30 External Timing Parameters *Notes (1), (2)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
t_{DRR}		8.0		9.5		12.5	ns
$t_{INSU}^{(3)}$	2.1		2.5		3.9		ns
$t_{INH}^{(3)}$	0.0		0.0		0.0		ns
$t_{OUTCO}^{(3)}$	2.0	4.9	2.0	5.9	2.0	7.6	ns
$t_{INSU}^{(4)}$	1.1		1.5		–		ns
$t_{INH}^{(4)}$	0.0		0.0		–		ns
$t_{OUTCO}^{(4)}$	0.5	3.9	0.5	4.9	–	–	ns
t_{PCISU}	3.0		4.2		–		ns
t_{PCIH}	0.0		0.0		–		ns
t_{PCICO}	2.0	6.0	2.0	7.5	–	–	ns

Table 43. EP1K30 External Bidirectional Timing Parameters *Notes (1), (2)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}}$ (3)	2.8		3.9		5.2		ns
$t_{\text{INHIBIDIR}}$ (3)	0.0		0.0		0.0		ns
$t_{\text{INSUBIDIR}}$ (4)	3.8		4.9		–		ns
$t_{\text{INHIBIDIR}}$ (4)	0.0		0.0		–		ns
$t_{\text{OUTCOBIDIR}}$ (3)	2.0	4.9	2.0	5.9	2.0	7.6	ns
t_{XZBIDIR} (3)		6.1		7.5		9.7	ns
t_{ZXBIDIR} (3)		6.1		7.5		9.7	ns
$t_{\text{OUTCOBIDIR}}$ (4)	0.5	3.9	0.5	4.9	–	–	ns
t_{XZBIDIR} (4)		5.1		6.5		–	ns
t_{ZXBIDIR} (4)		5.1		6.5		–	ns

Notes to tables:

- (1) All timing parameters are described in Tables 22 through 29 in this data sheet.
- (2) These parameters are specified by characterization.
- (3) This parameter is measured without the use of the ClockLock or ClockBoost circuits.
- (4) This parameter is measured with the use of the ClockLock or ClockBoost circuits.

Tables 44 through 50 show EP1K50 device external timing parameters.

Table 44. EP1K50 Device LE Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		0.6		0.8		1.1	ns
t_{CLUT}		0.5		0.6		0.8	ns
t_{RLUT}		0.6		0.7		0.9	ns
t_{PACKED}		0.2		0.3		0.4	ns
t_{EN}		0.6		0.7		0.9	ns
t_{CICO}		0.1		0.1		0.1	ns
t_{CGEN}		0.4		0.5		0.6	ns
t_{CGENR}		0.1		0.1		0.1	ns
t_{CASC}		0.5		0.8		1.0	ns
t_{C}		0.5		0.6		0.8	ns

Table 53. EP1K100 Device EAB Internal Microparameters *Note (1)*

Symbol	Speed Grade						Unit
	-1		-2		-3		
	Min	Max	Min	Max	Min	Max	
$t_{EABDATA1}$		1.5		2.0		2.6	ns
$t_{EABDATA1}$		0.0		0.0		0.0	ns
t_{EABWE1}		1.5		2.0		2.6	ns
t_{EABWE2}		0.3		0.4		0.5	ns
t_{EABRE1}		0.3		0.4		0.5	ns
t_{EABRE2}		0.0		0.0		0.0	ns
t_{EABCLK}		0.0		0.0		0.0	ns
t_{EABCO}		0.3		0.4		0.5	ns
$t_{EABYPASS}$		0.1		0.1		0.2	ns
t_{EABSU}	0.8		1.0		1.4		ns
t_{EABH}	0.1		0.1		0.2		ns
t_{EABCLR}	0.3		0.4		0.5		ns
t_{AA}		4.0		5.1		6.6	ns
t_{WP}	2.7		3.5		4.7		ns
t_{RP}	1.0		1.3		1.7		ns
t_{WDSU}	1.0		1.3		1.7		ns
t_{WDH}	0.2		0.2		0.3		ns
t_{WASU}	1.6		2.1		2.8		ns
t_{WAH}	1.6		2.1		2.8		ns
t_{RASU}	3.0		3.9		5.2		ns
t_{RAH}	0.1		0.1		0.2		ns
t_{WO}		1.5		2.0		2.6	ns
t_{DD}		1.5		2.0		2.6	ns
t_{EABOUT}		0.2		0.3		0.3	ns
t_{EABCH}	1.5		2.0		2.5		ns
t_{EABCL}	2.7		3.5		4.7		ns